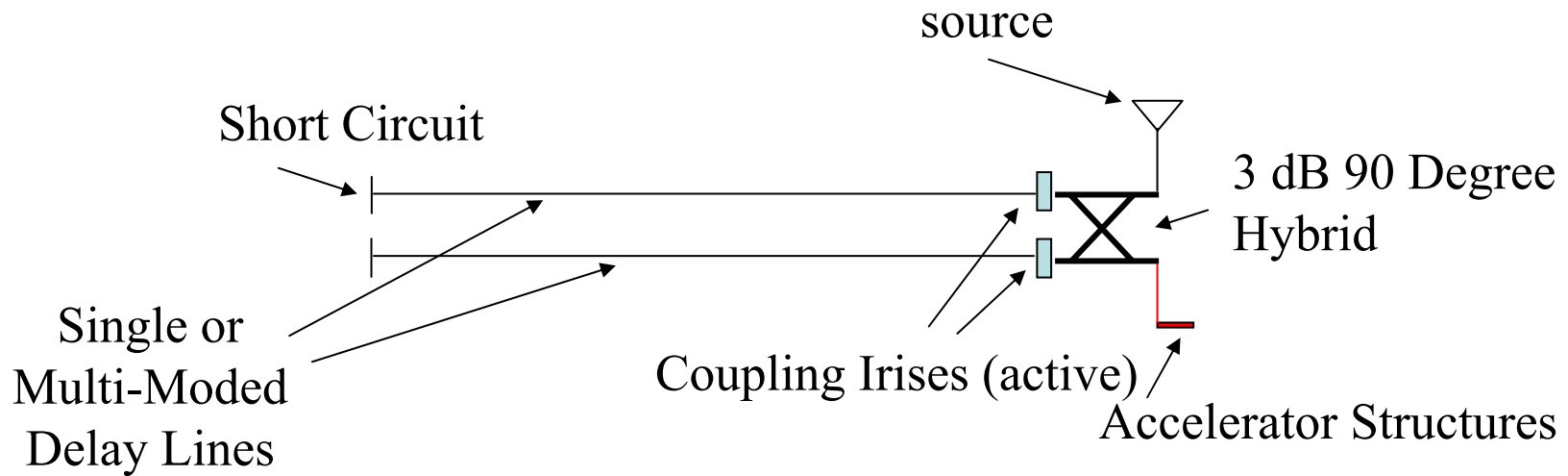
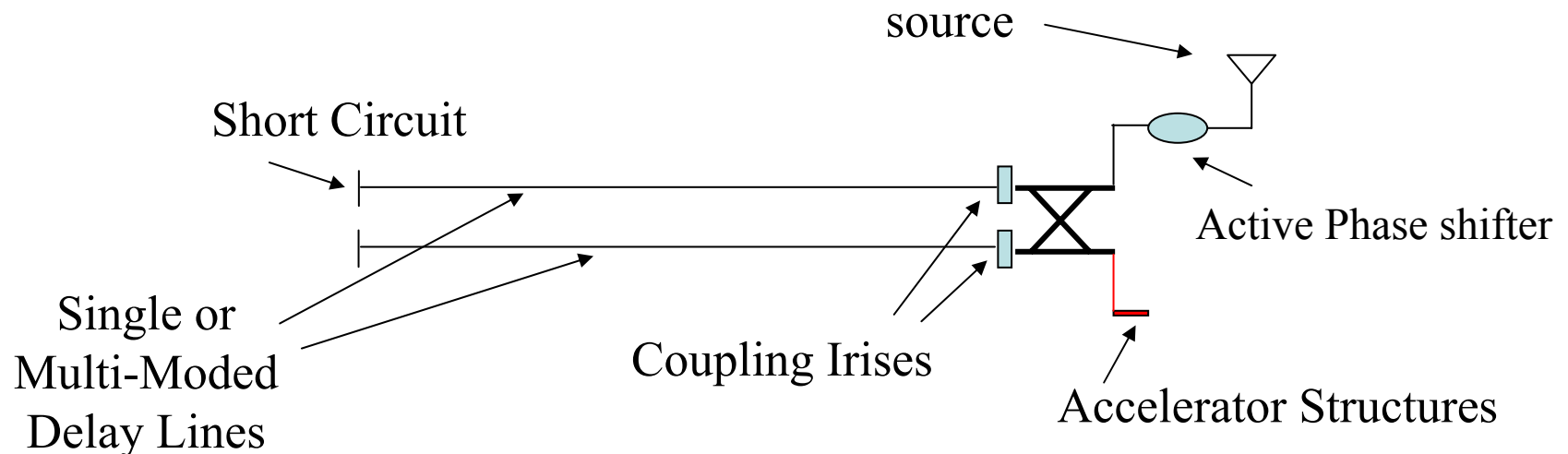


Active Pulse Compression for Oscillator Systems at 30GHz

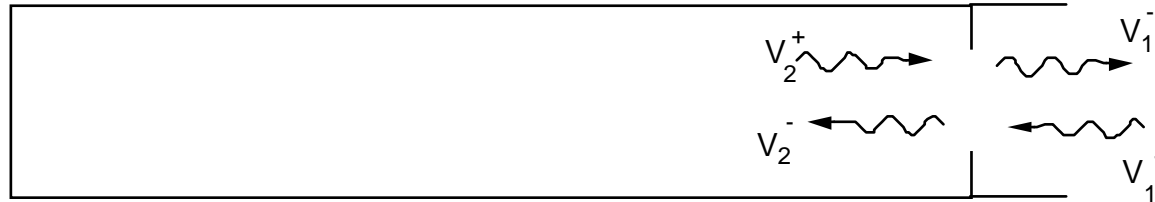
Sami Tantawi
SLAC



a) Sled-II Pulse compression system with active iris



b) Sled-II Pulse compression system with active phase shifter



Resonant delay line.

$$\underline{S} = \begin{pmatrix} -R_0 & -j(1-R_0^2)^{1/2} \\ -j(1-R_0^2)^{1/2} & -R_0 \end{pmatrix}$$

$$V_1^- = -R_0 V_1^+ - j(1-R_0^2)^{1/2} V_2^+,$$

$$V_2^- = -j(1-R_0^2)^{1/2} V_1^+ - R_0 V_2^+.$$

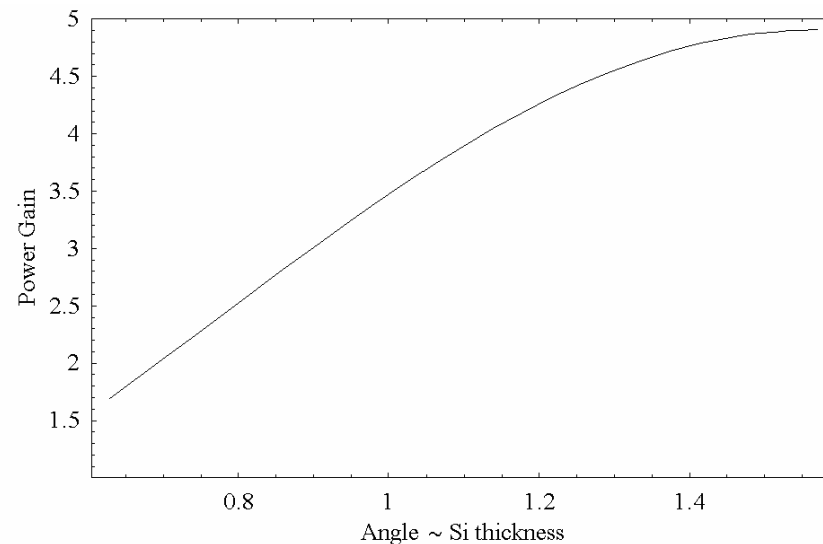
$$V_2^+(t) = V_2^-(t - \tau) e^{-j2\beta l}.$$

Discharging By Active Switching

To discharge the line, one can keep the input signal at a constant level during the time interval $0 \leq t < n\tau$ but switching the iris reflection coefficient to zero so that all the energy stored in the line is dumped out. In this case

$$V_{out} = \frac{1 - (R_0 p)^n}{1 - R_0 p} (1 - R_0^2)^{1/2} p V_{in}.$$

So, what happens if we do not switch the iris reflection coefficient all the way to zero?



Switching Just Before The Last Time Bin

To reduce the burden on the switch one can indeed utilize the ingenious idea of reversing the phase together with changing the iris reflection coefficient.

$$R_d = \cos \left[\tan^{-1} \left(\frac{1 - (R_0 p)^{n-1}}{1 - R_0 p} (1 - R_0^2)^{1/2} p \right) \right].$$

This new reflection coefficient is greater than zero and the switch need only change the iris between R_0 and R_d .

$$V_{out} = R_d \left[1 + \left(\frac{1 - (R_0 p)^{n-1}}{1 - R_0 p} \right)^2 (1 - R_0^2) p^2 \right] V_{in}.$$

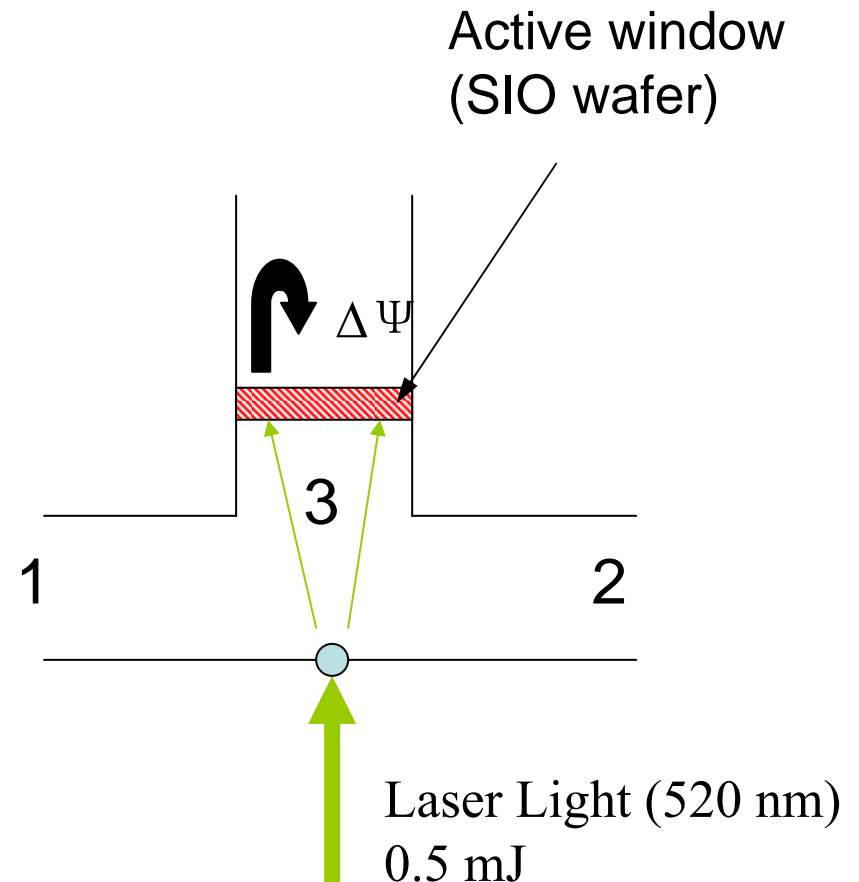
The compressed pulse takes place in the interval $(n - 1) \tau \leq t < n \tau$. The optimum value of R_0 is such that it fills the system with maximum possible amount of energy in the time interval $(n - 1) \tau$ instead of $n \tau$ in the previous case.

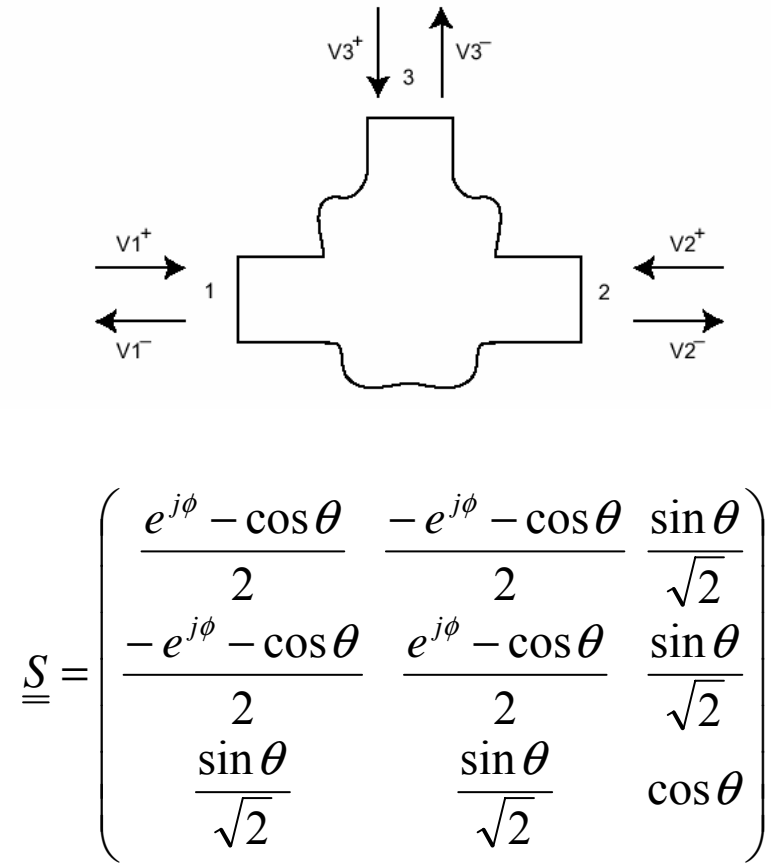
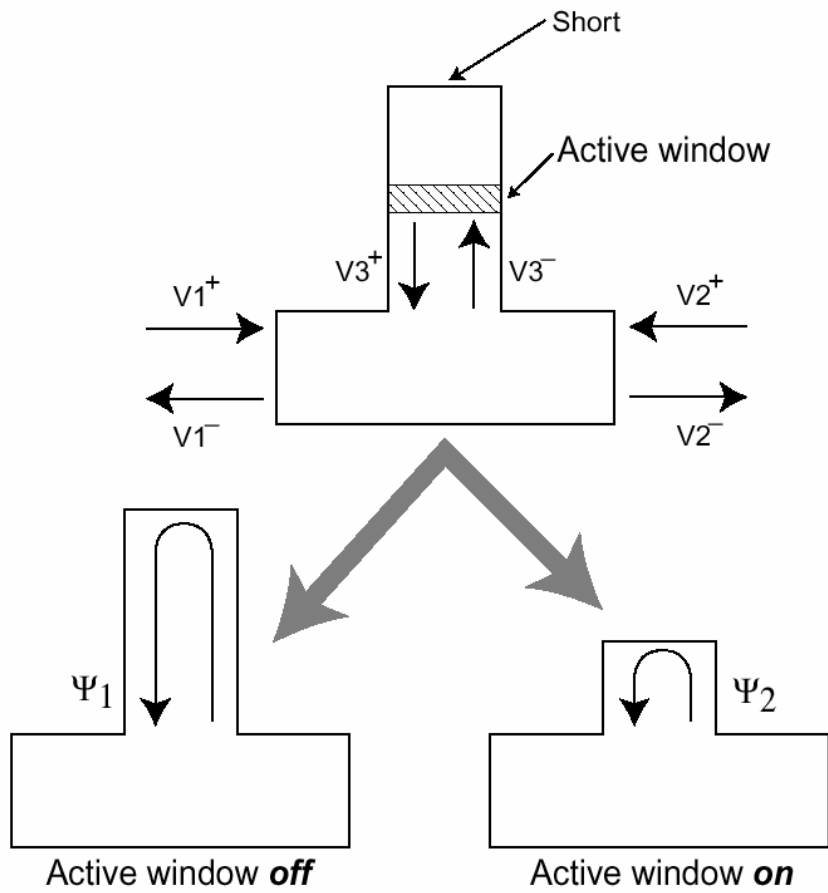
Cr	SLED II		Switching During		Discharging After		Discharging Just		
	η (%)	Opt. R_0	η (%)	Opt. R_0	η (%)	Opt. R_0	η (%)	Opt. R_0	R_d
2	78.1	0.5	100	0.707	84.4	0.5	100	0.0	0.707
3	88.7	0.548	98.9	0.631	82.7	0.646	89.6	0.5	0.610
4	86.0	0.607	92.6	0.658	82.1	0.725	87.0	0.646	0.536
5	80.4	0.651	85.1	0.688	81.9	0.775	85.7	0.725	0.483
6	74.6	0.685	78.1	0.714	81.8	0.809	84.9	0.775	0.443
8	64.4	0.733	66.5	0.754	81.6	0.854	84.0	0.835	0.386
10	56.2	0.767	57.7	0.783	81.6	0.882	83.4	0.869	0.346
12	49.9	0.792	50.9	0.805	81.5	0.900	83.1	0.892	0.317
16	40.6	0.828	41.2	0.837	81.5	0.924	82.7	0.920	0.275
24	29.6	0.869	29.8	0.875	81.5	0.949	82.2	0.947	0.225
32	23.3	0.893	23.4	0.897	81.5	0.961	82.0	0.960	0.195
64	12.6	0.936	12.7	0.938	81.5	0.981	81.7	0.980	0.138
128	6.6	0.962	6.6	0.963	81.5	0.990	81.6	0.990	0.099
256	3.4	0.978	3.4	0.979	81.5	0.995	81.5	0.995	0.069

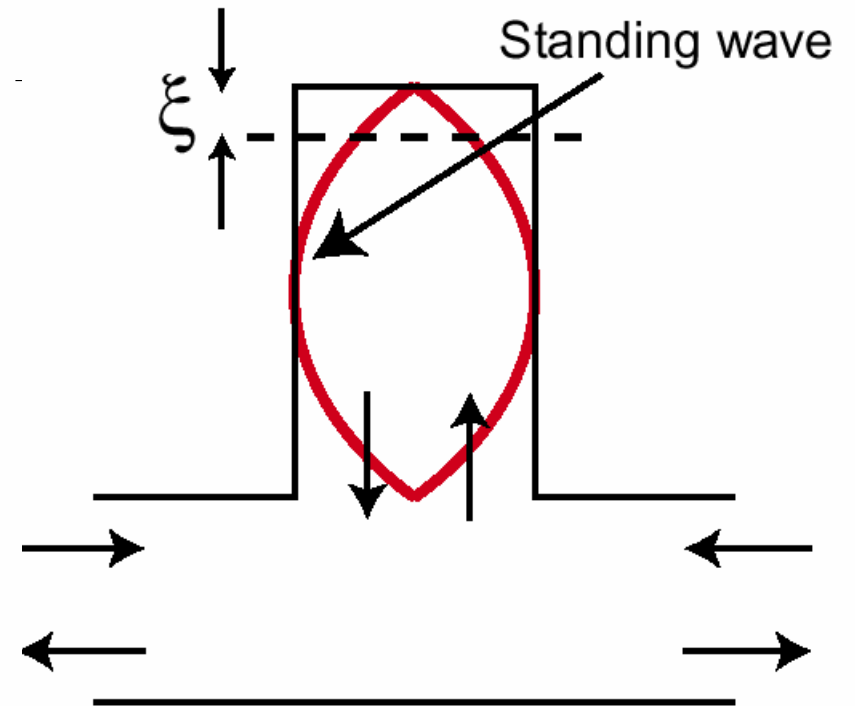
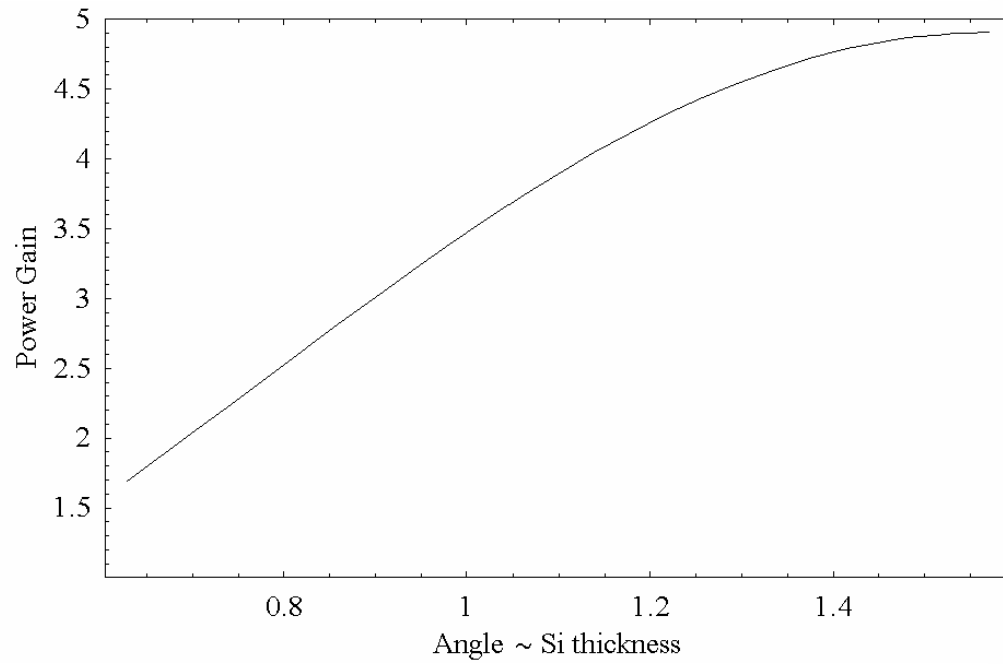
Comparison between different methods of single event switching pulse compression systems.

Design of the Switch Module (Suitable for high frequencies)

- Switch the S matrix of the two port network by changing the reflection phase in the 3rd arm
- The S matrix of ON state is tuned by the location of the active window.
- OFF state is tuned by the movable short shown.





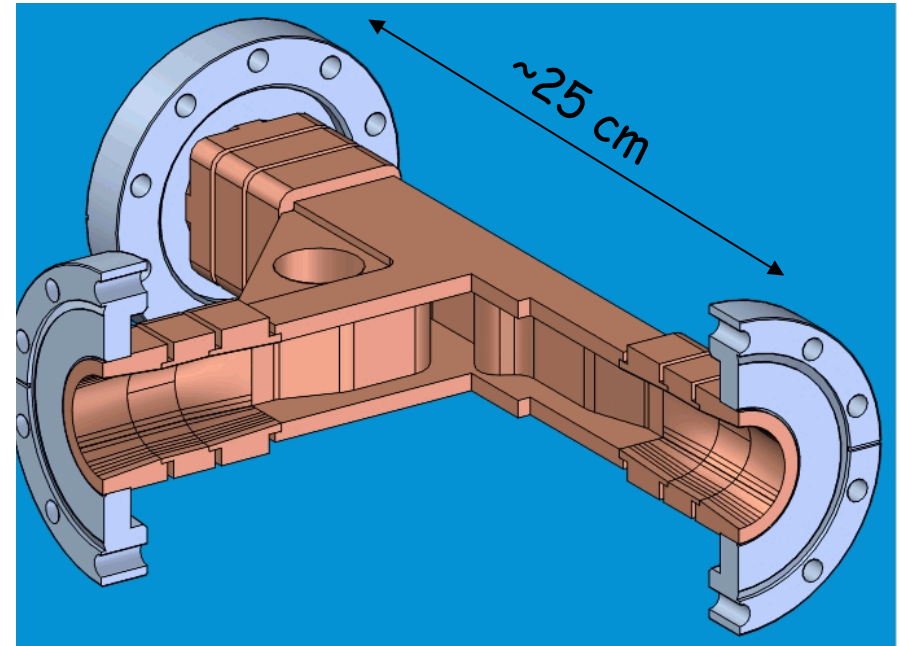
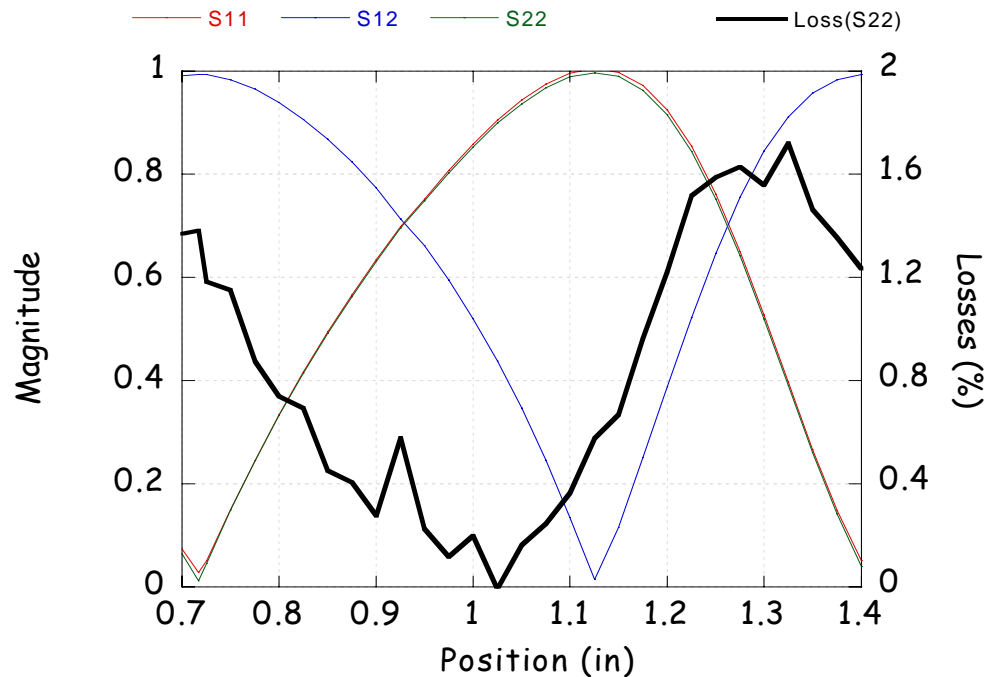


$$|V_3| = 2|V_3^-| |\sin \beta_3 \xi|$$

$$E_{max} = 2 \sqrt{\frac{1 + 2 \cos \theta \cos \zeta + \cos^2 \theta}{2 \sin^2 \theta}} |\sin \beta_3 \xi| \sqrt{\frac{P_{in} Z_g}{AG}}$$

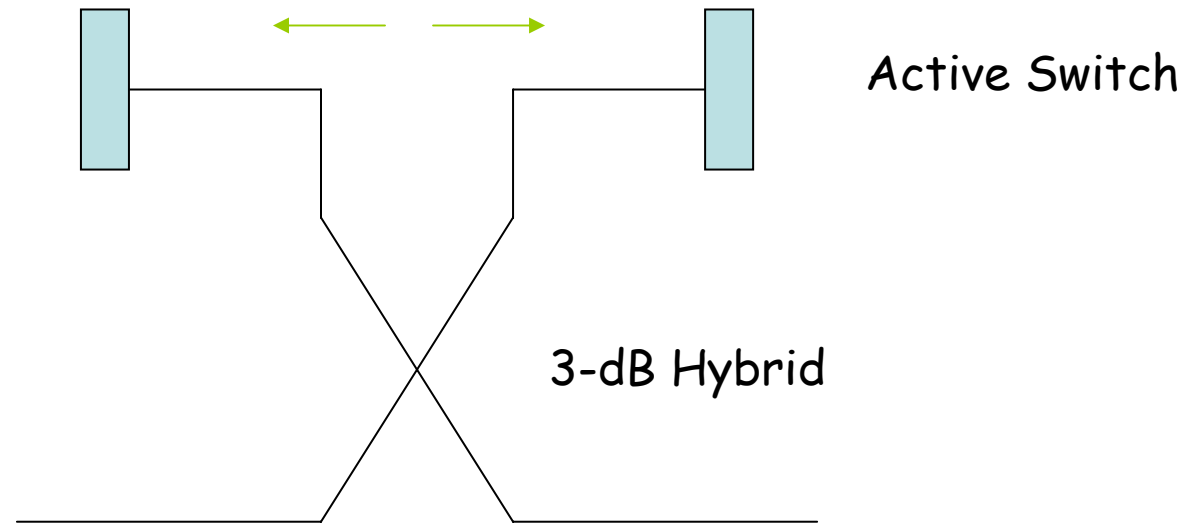
$$P_l = 4 \frac{(1 + 2 \cos \theta \cos \zeta + \cos^2 \theta) R_s}{2 \sin^2 \theta} \frac{R_s}{Z_g} |V_1^+ + V_2^+|^2$$

TE_{01} Mode Tee (Variable Iris)



- The Tee body is planer rectangular guide operating in the TE_{20}
- We Taper from Circular to Rectangular with a special taper which generate the TE_{01} mode

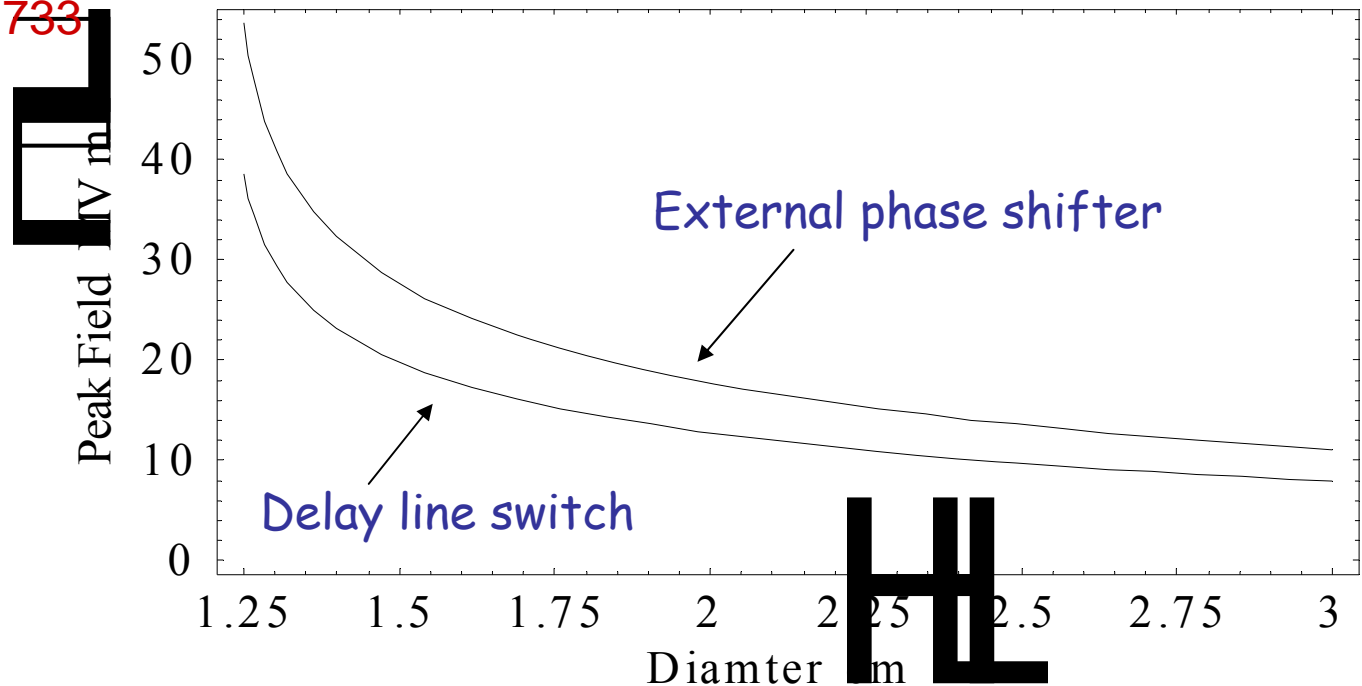
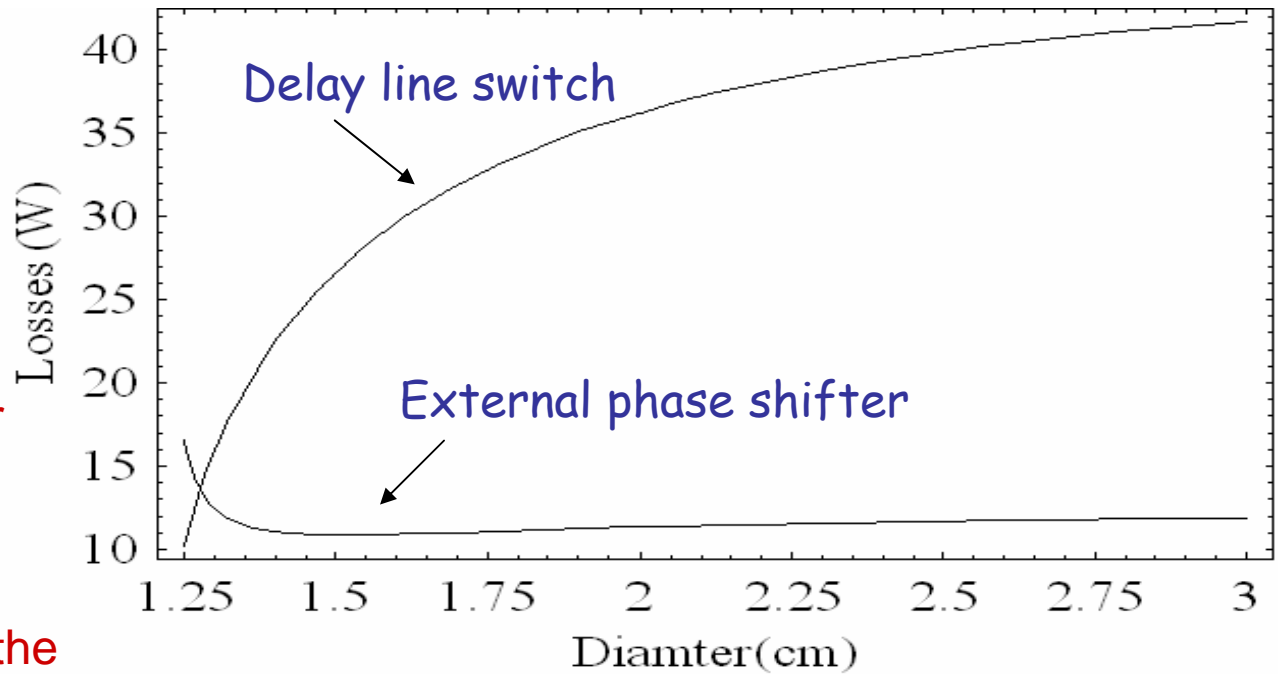
Pi Phase Shifter

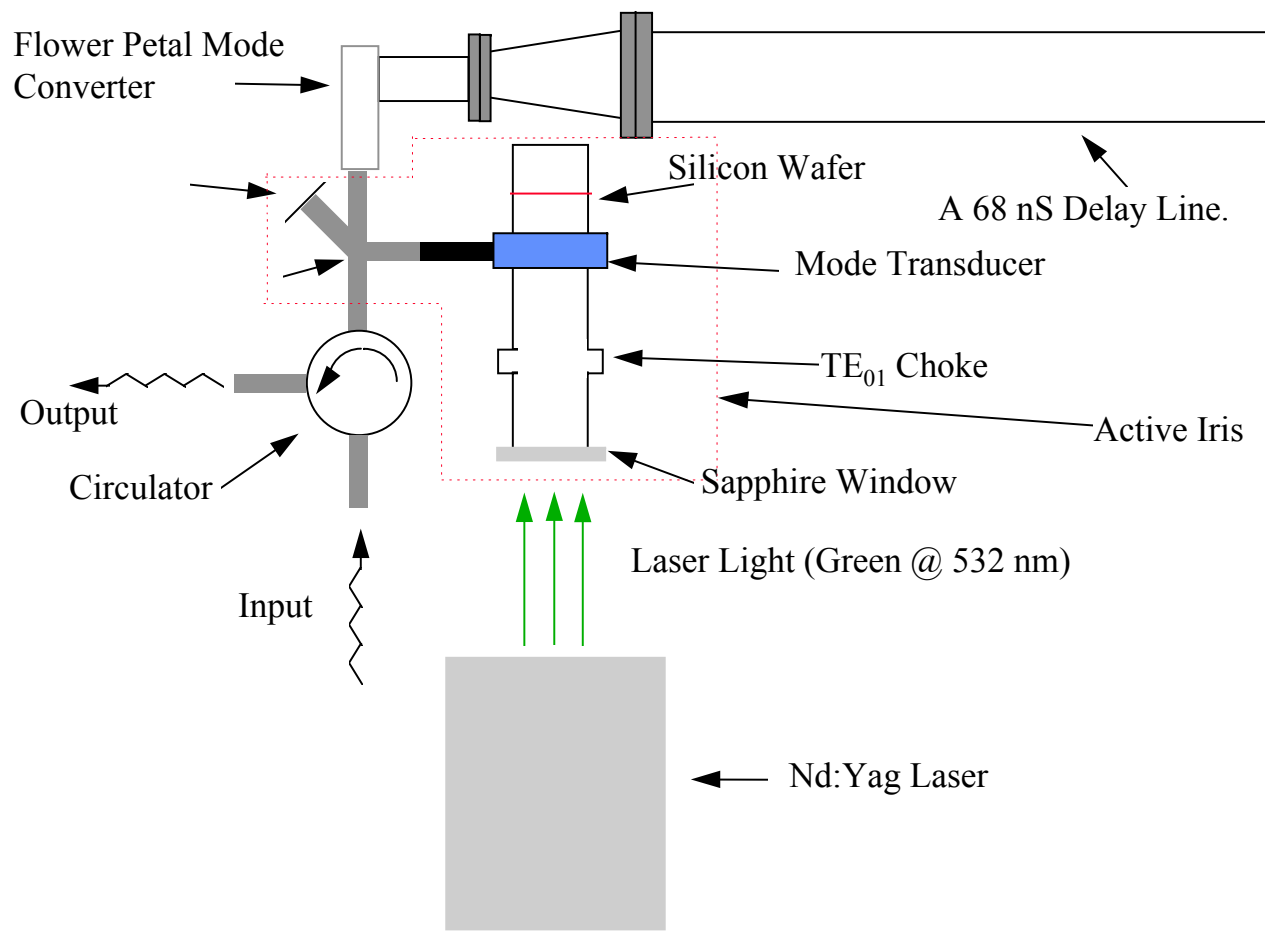


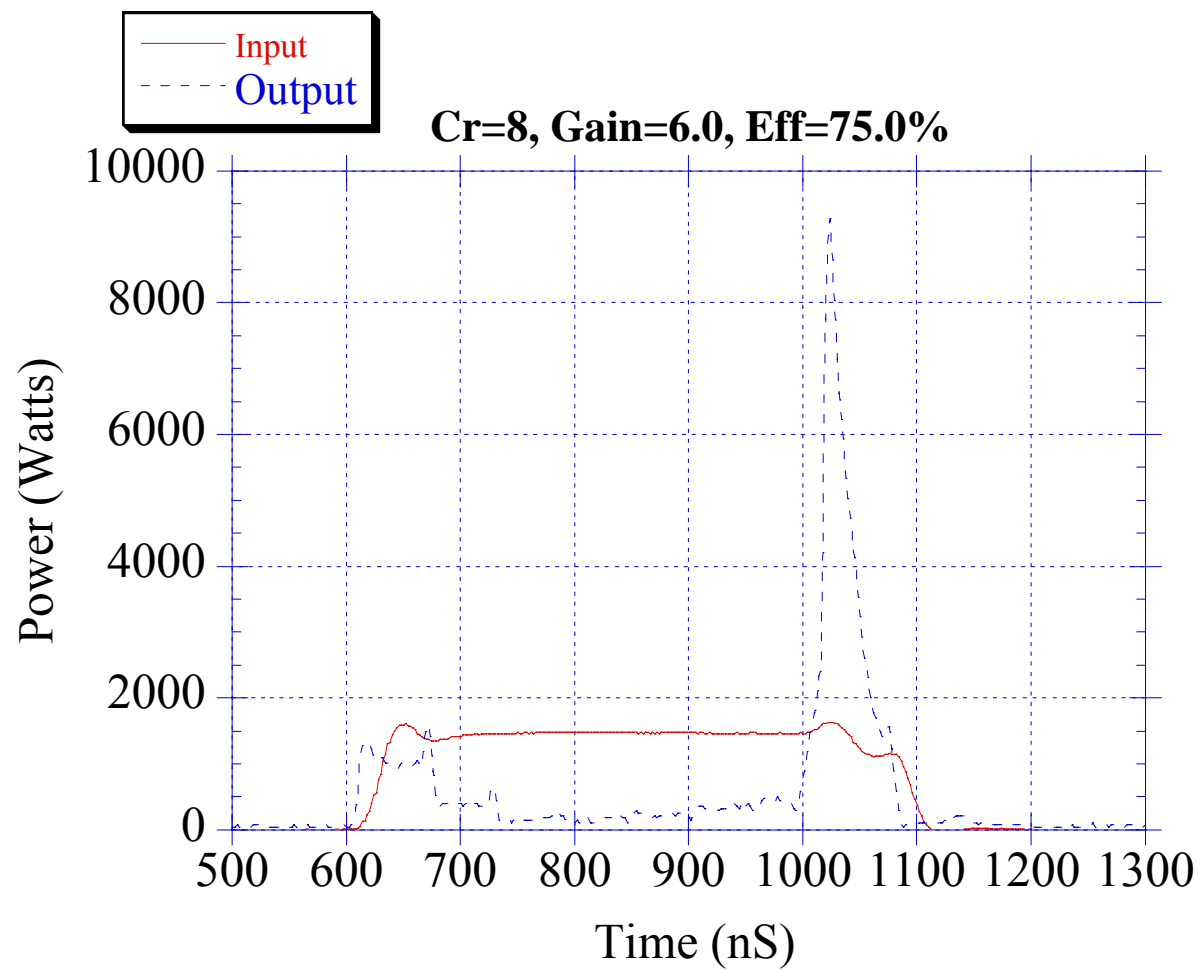
The switch has to change the phase by π . The thickness of the of the Si wafer is ~ 730 micron

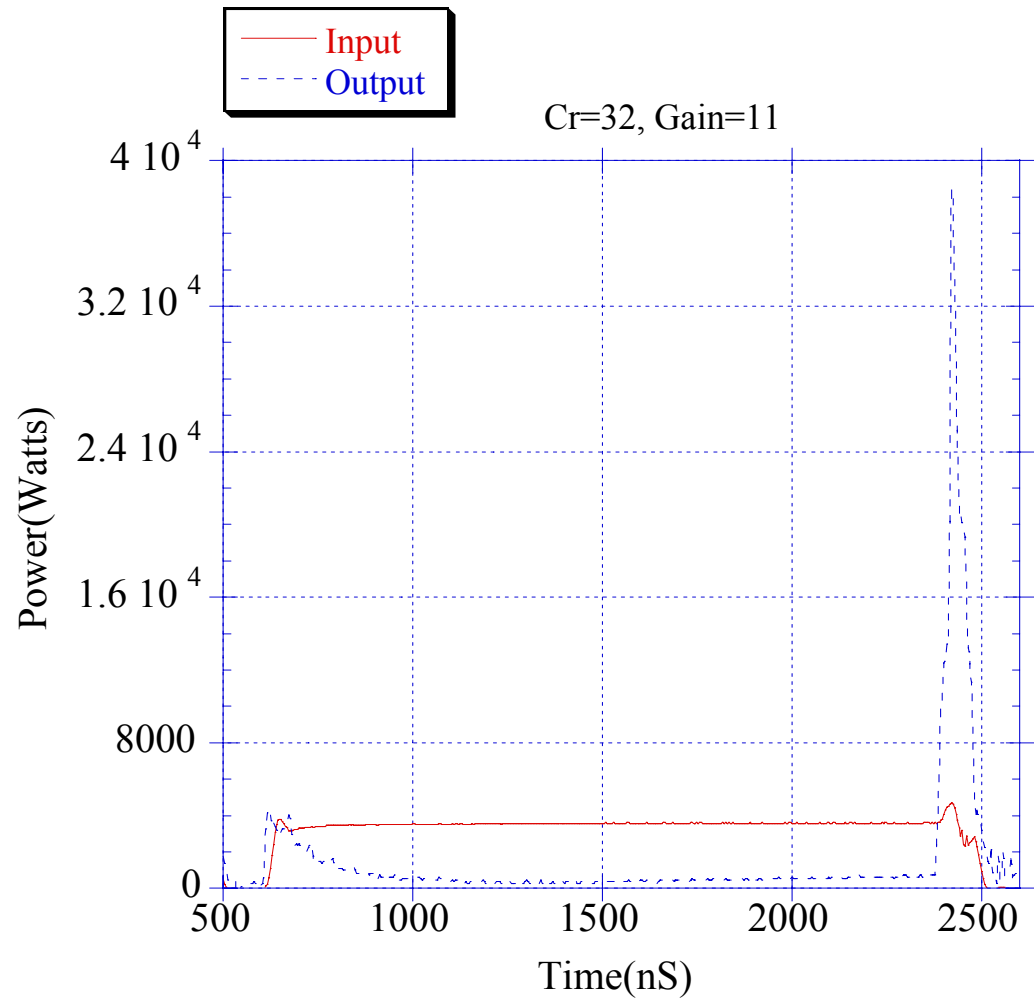
Silicon Wafer Thickness for delay line switch ~ 153 microns

Silicon wafer thickness for the external phase shifter ~ 733 microns

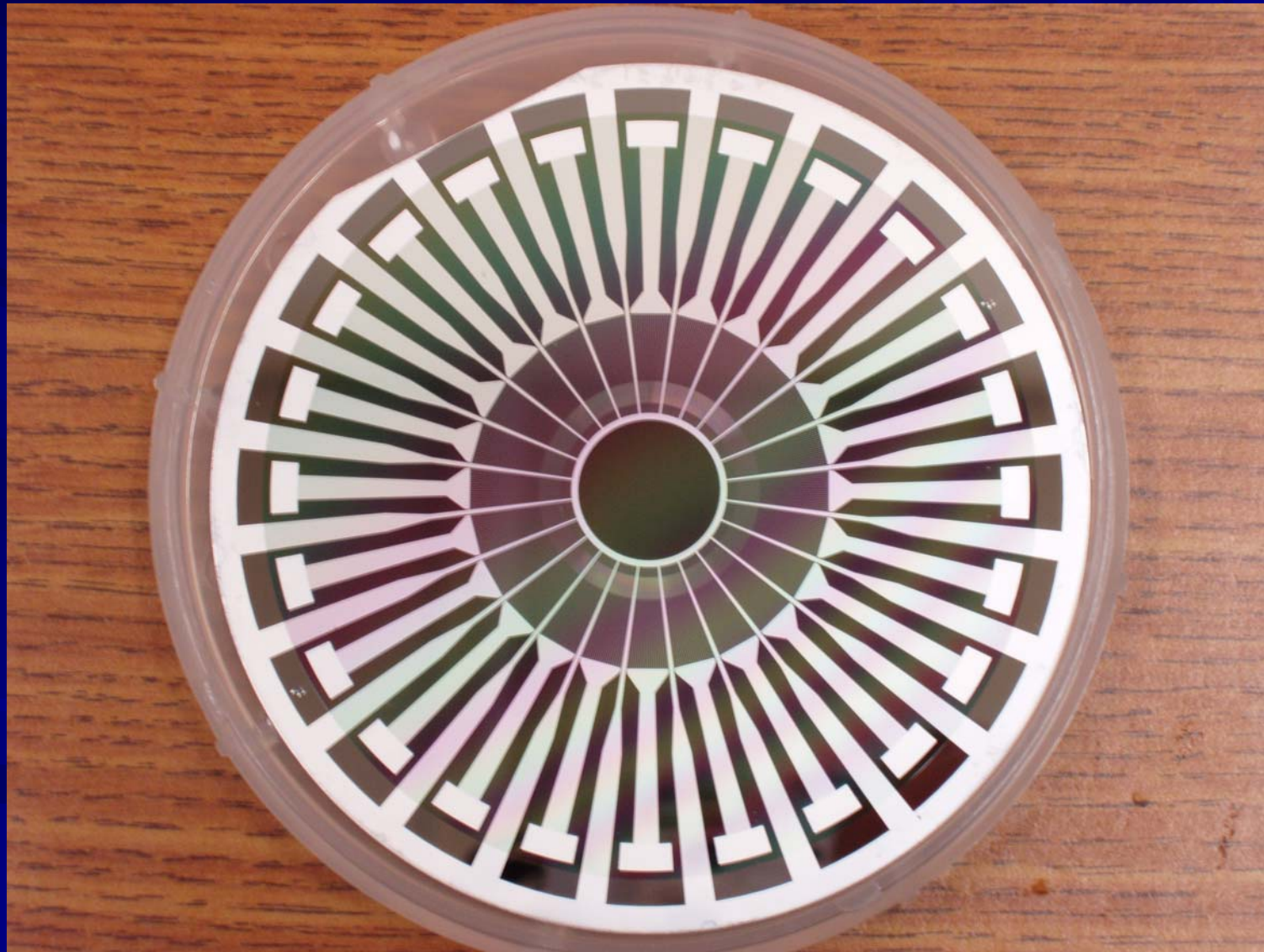








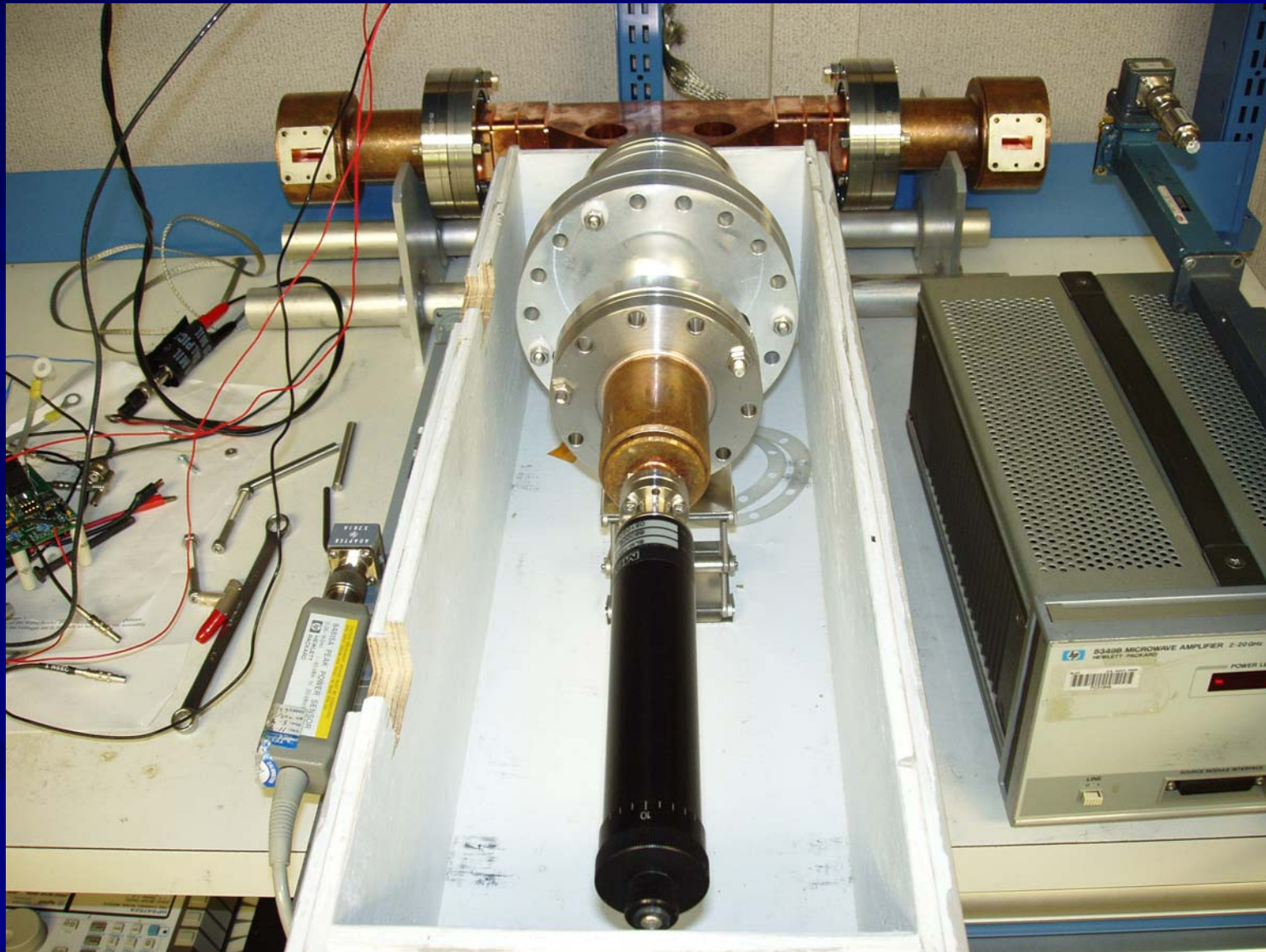
Diode array



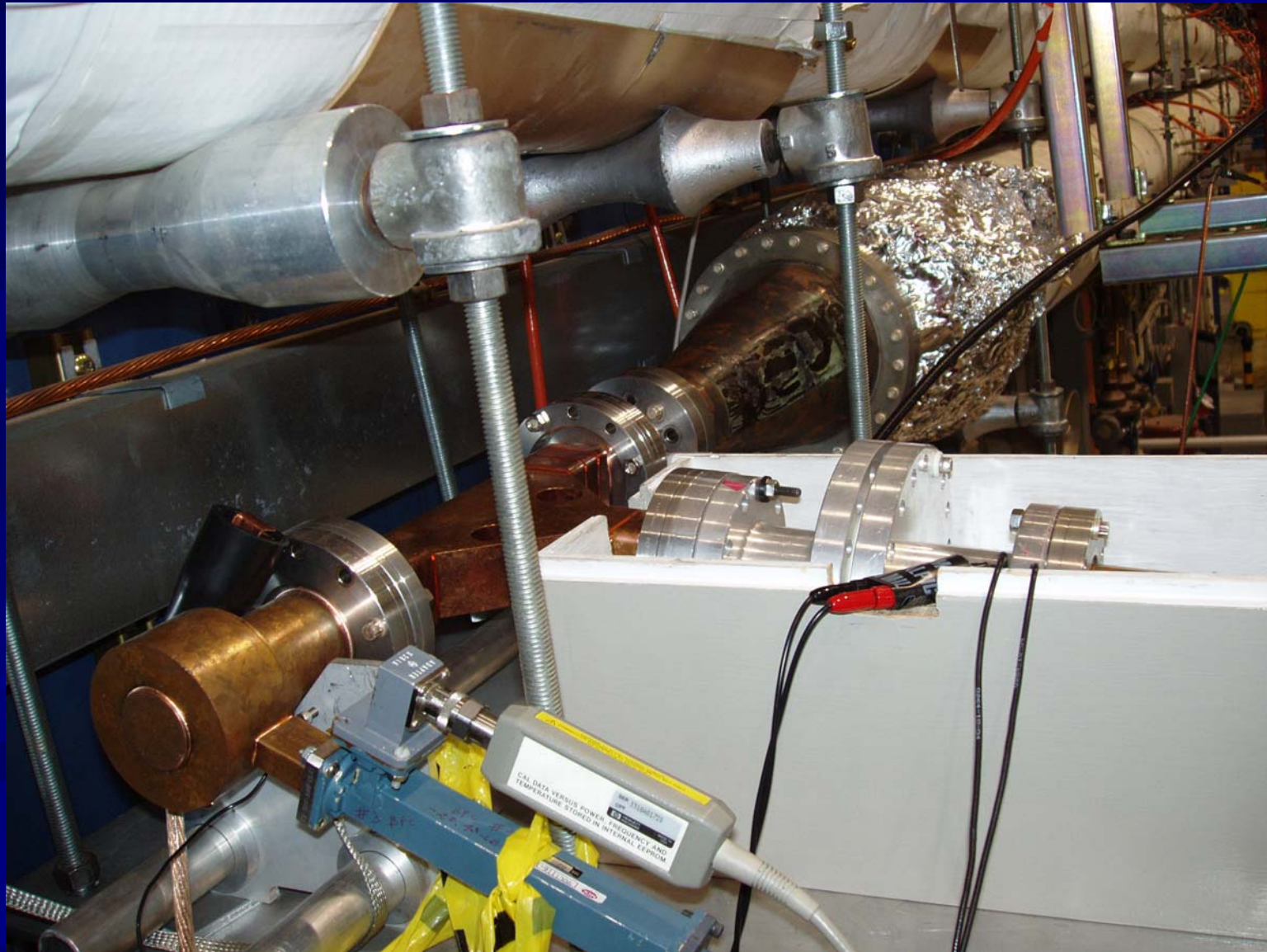
Testing structure



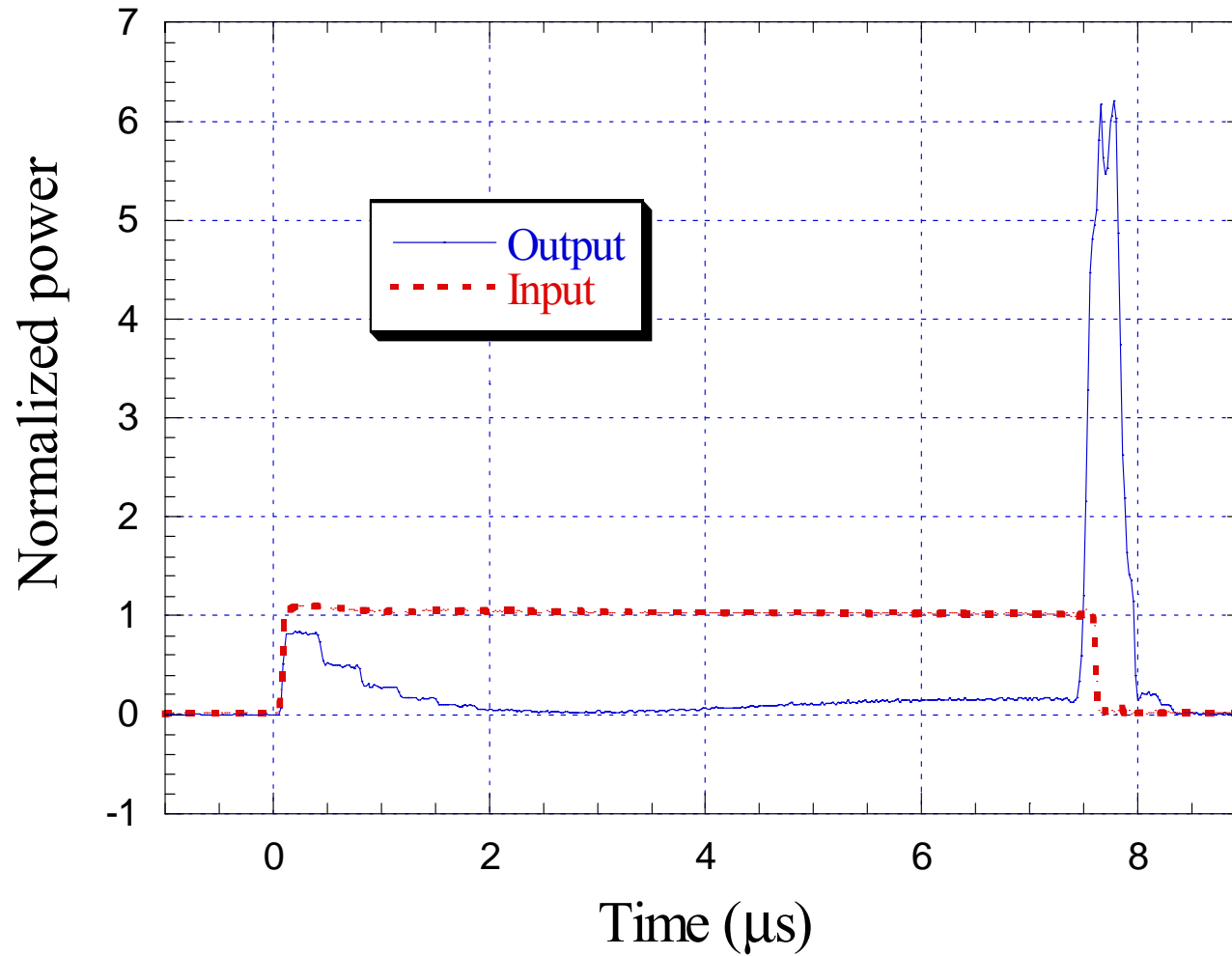
Test Setup with Circular T



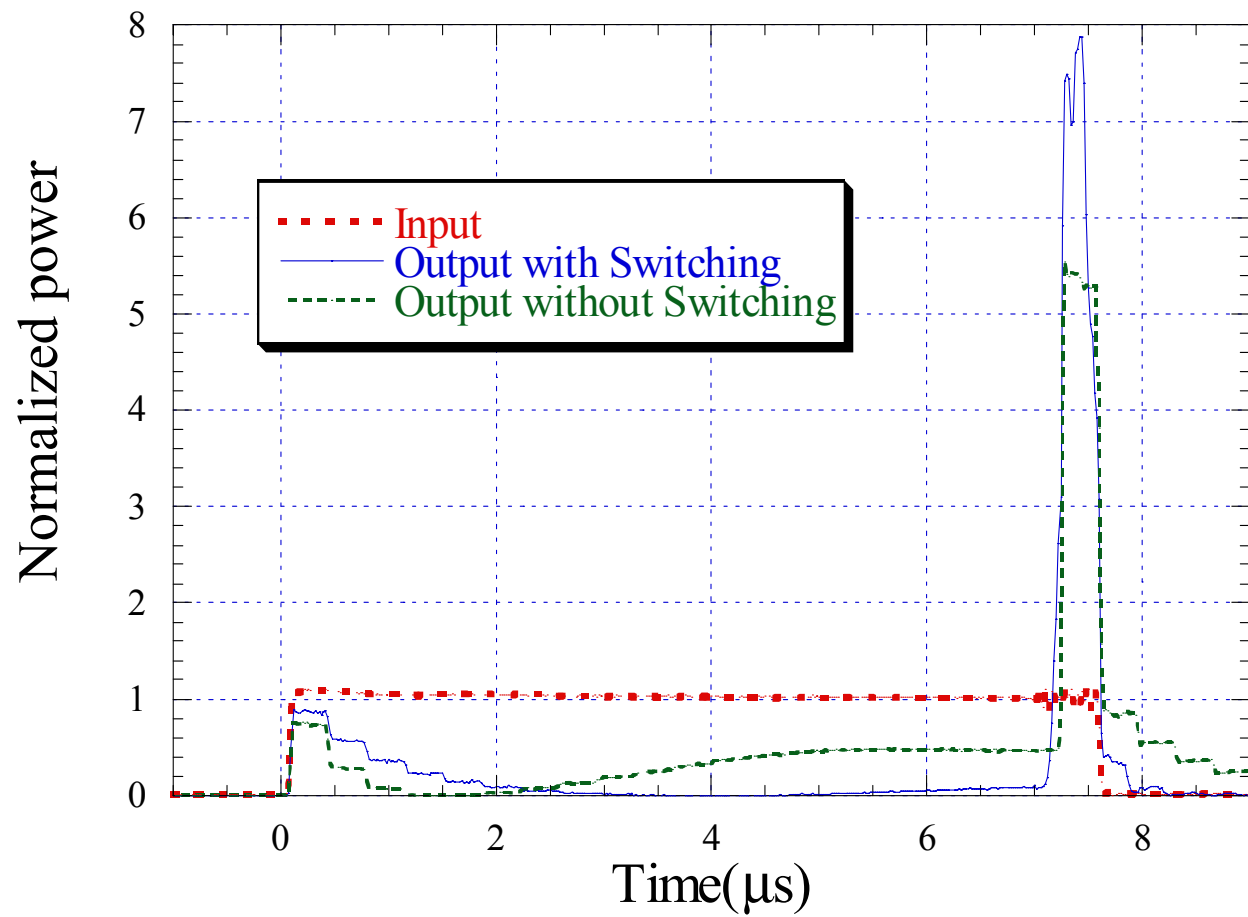
Active Compression Setup



Low Power Active Pulse Compression Test Without Input Phase Flipping



Low Power Active Compression Test With Input Phase Flipping



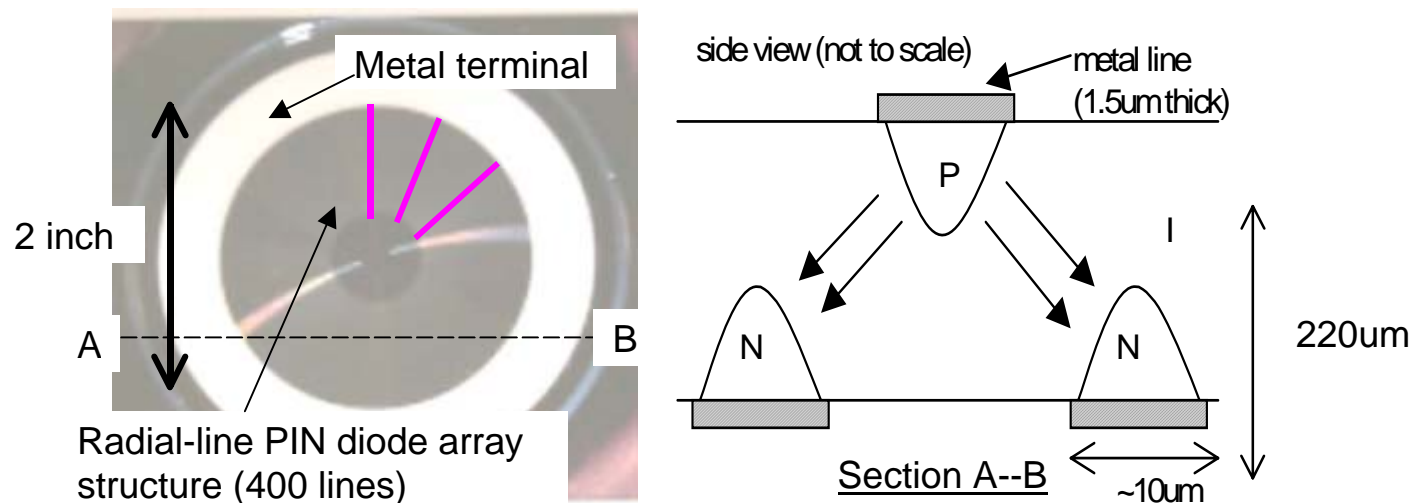
What should we do next

- Test the breakdown properties of Si
 - At X-band at SLAC
 - At Ka Band at CERN
- Real Thermal Analysis
- Chose a laser system (532 nm?)
- Enjoy a working active pulse compression system

Design and Implementation of PIN/NIP Diode Array Active Window

PIN diode array Active Window

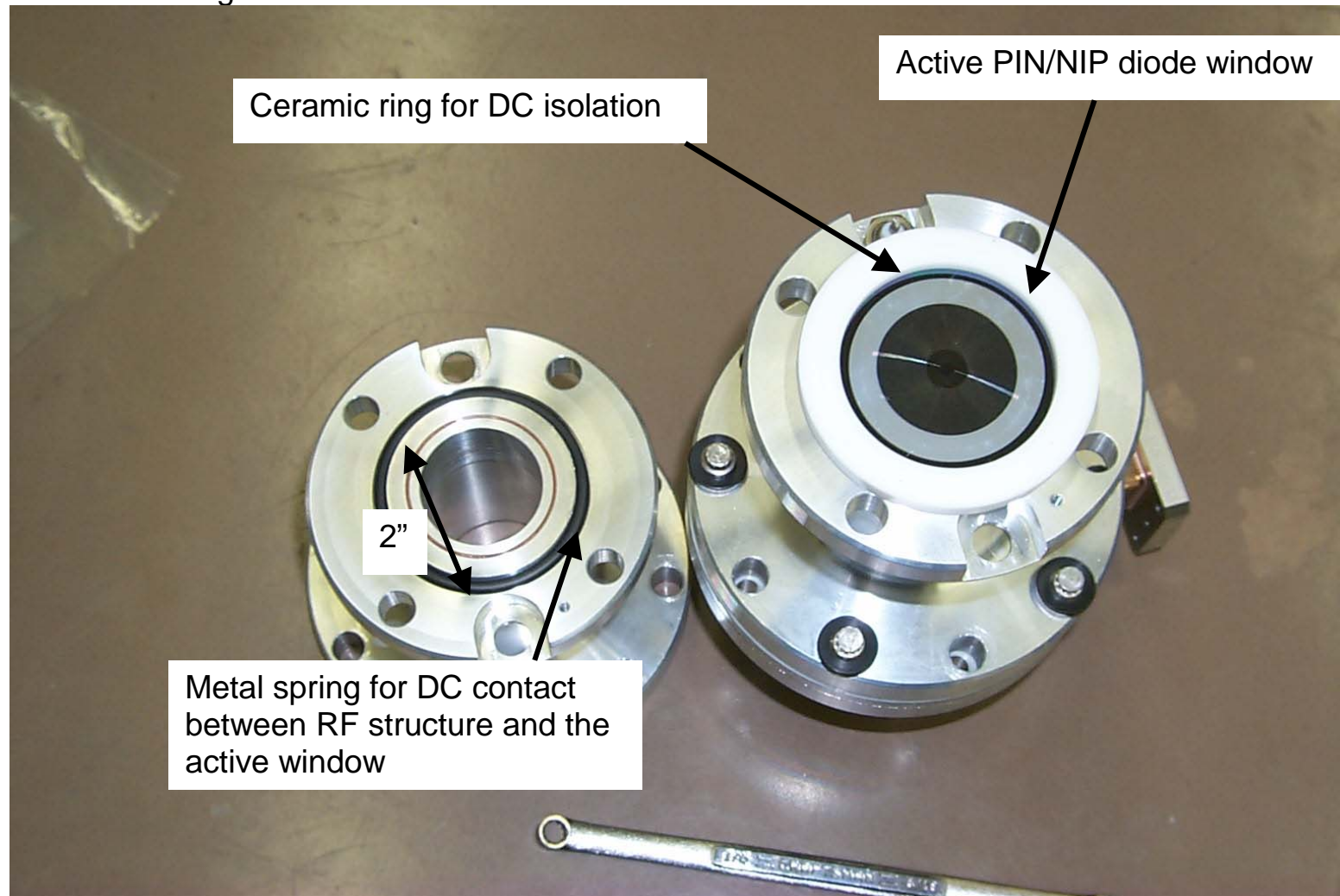
- All doping profile and metallic terminals on the window are radial, i.e. perpendicular to electric field of the TE_{01} mode. → Effect of doping and metal lines on RF signal is small when the diode is reverse biased.
- With forward bias, carriers are injected into I region and I region becomes conductor → RF signal is reflected.

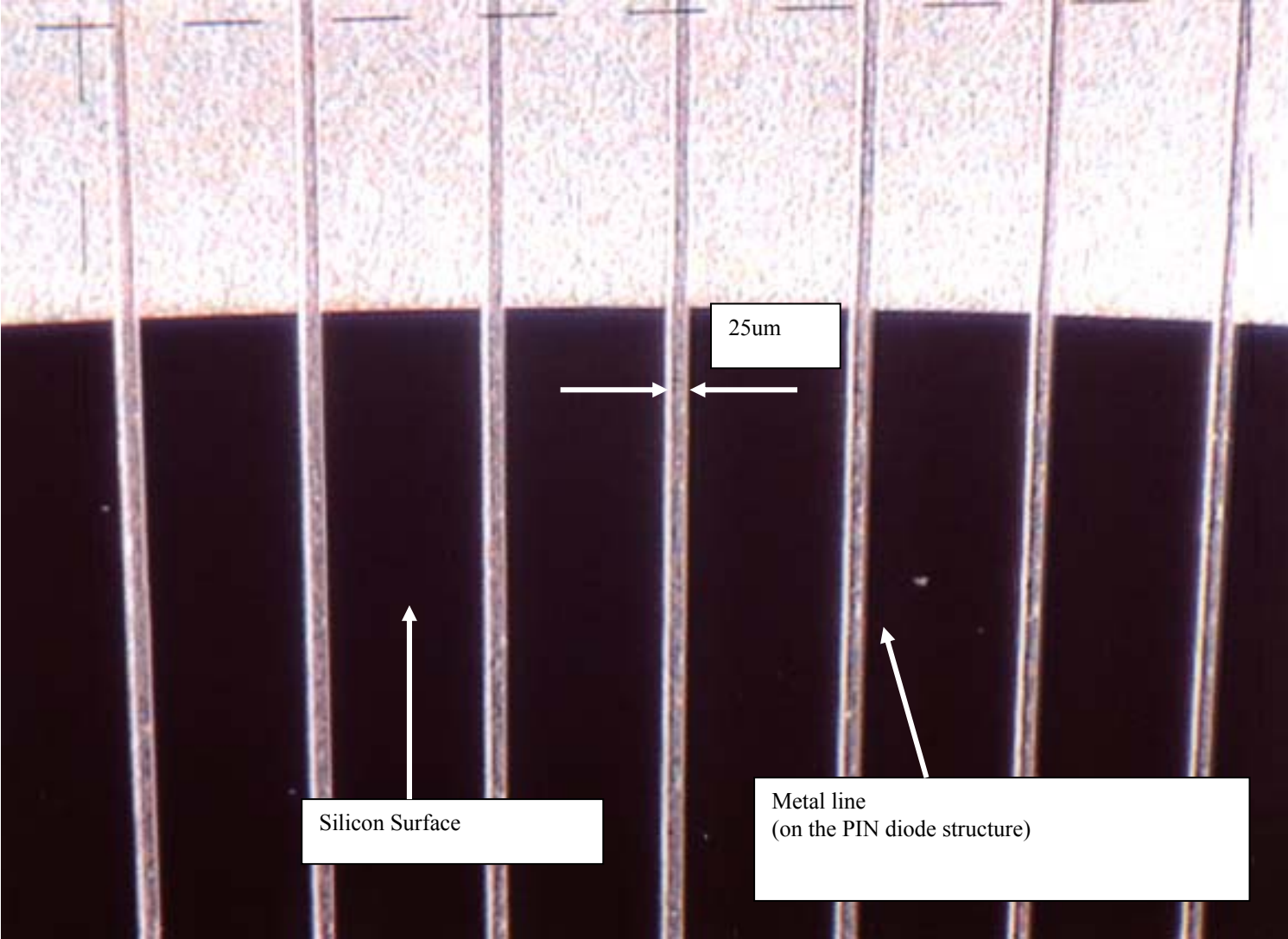


- Base material: high resistivity (pure) silicon, <math><5000\text{ohm-cm}</math>, n-type
- Diameter of active region: 1.3 inch
- Thickness: **220μm**
- Coverage (metal/doping line on the surface): ~10%

RF structure

- DC isolation by Al_2O_3 ceramic ring
- No RF choke is needed (TE_{01} mode)
- Higher impedance ($Z_g / Z_0 \sim 4$, close to cutoff) for this experiment
 - Enhance the effect of window switching status
 - Lower loss at the window during forward bias
 - Huge mismatch without bias





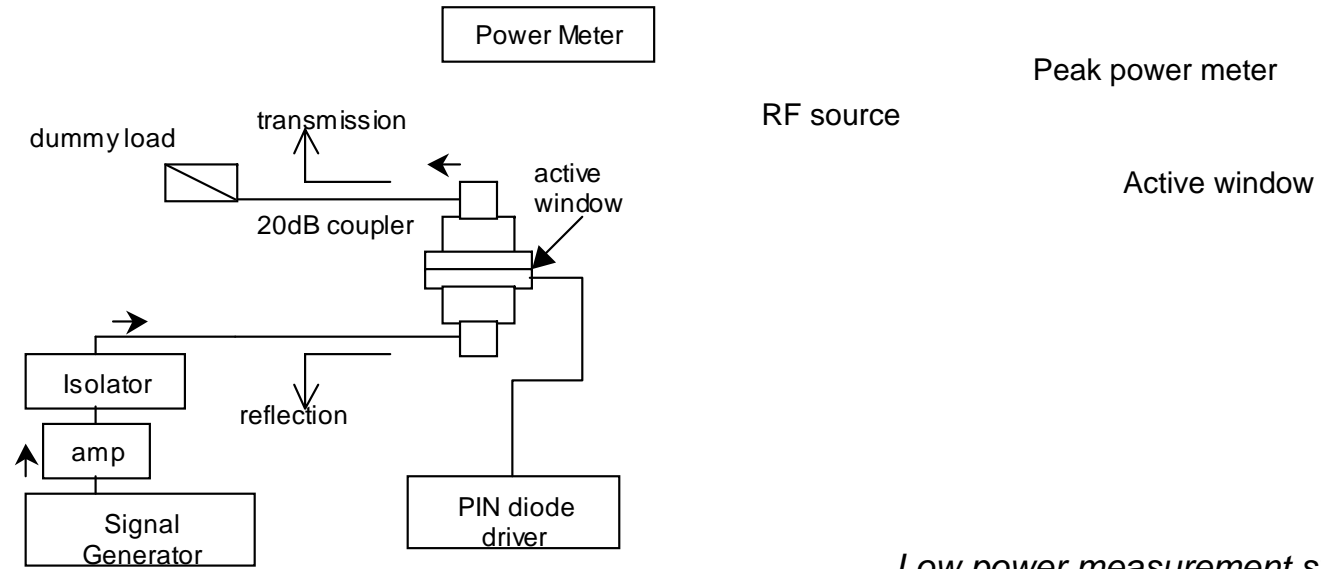
25um

Silicon Surface

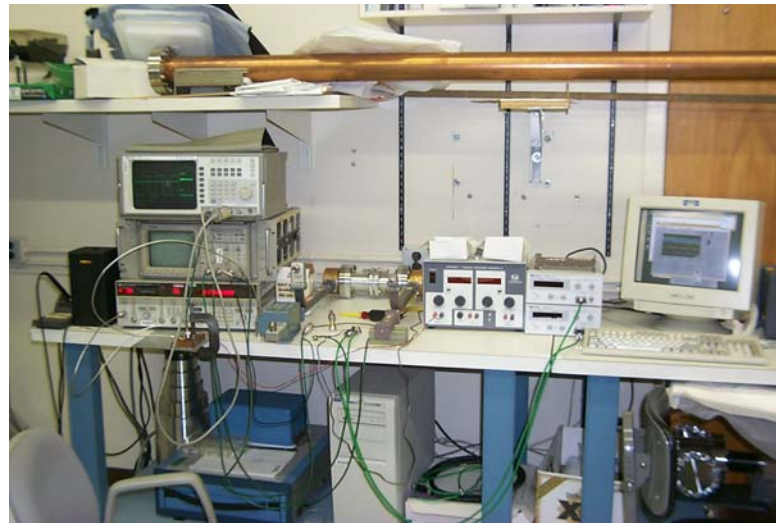
Metal line
(on the PIN diode structure)

Low Power Measurement

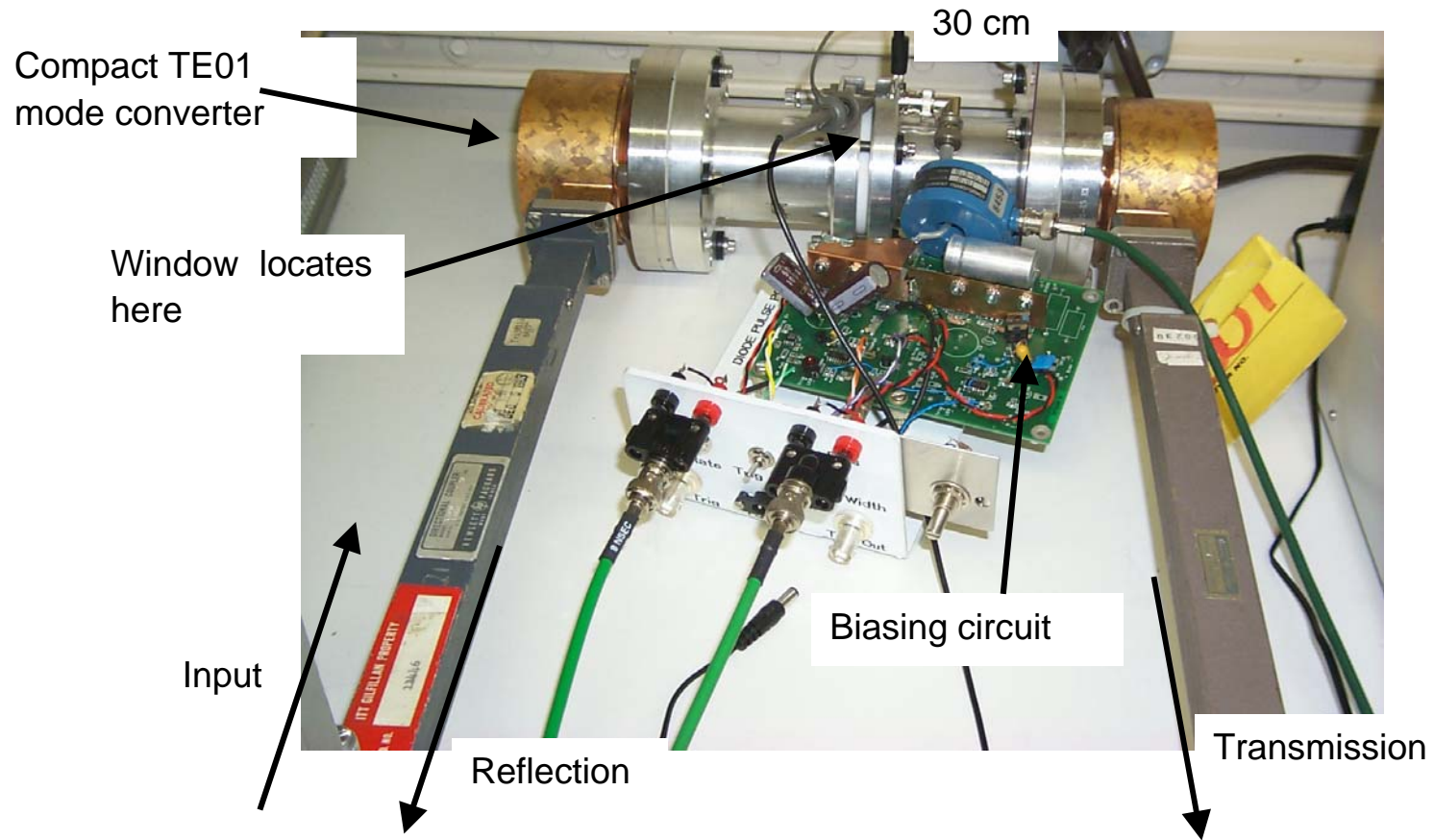
Setup:



Low power measurement system

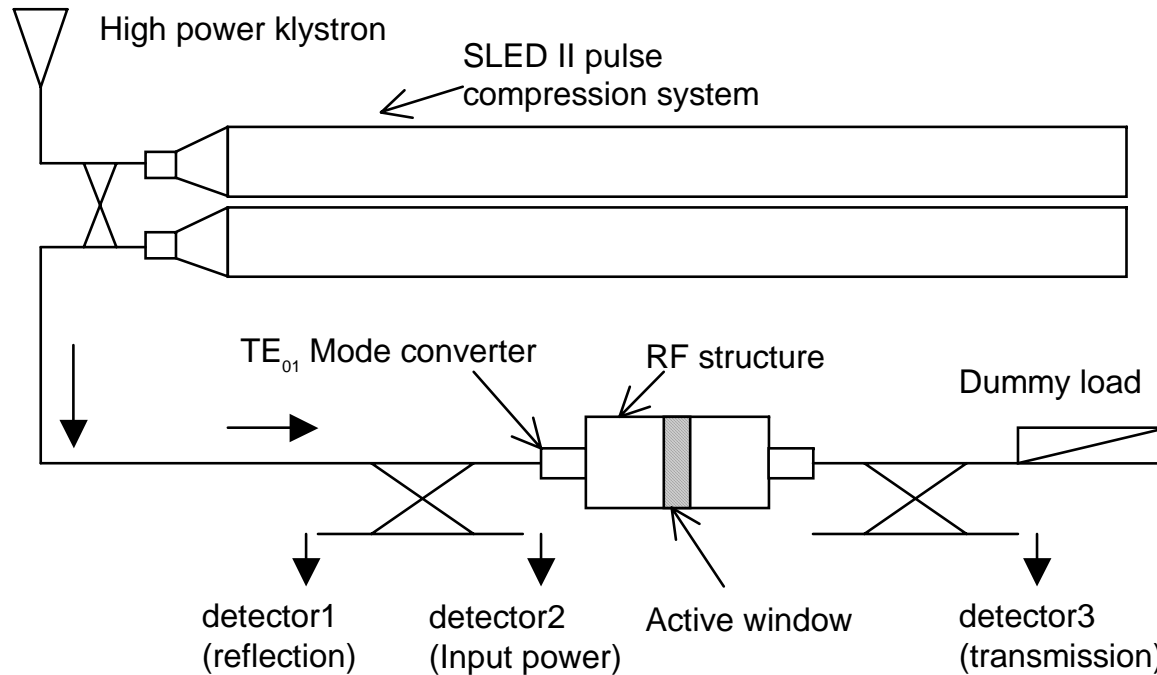


- Current is measured by current transformer



High Power Experiment

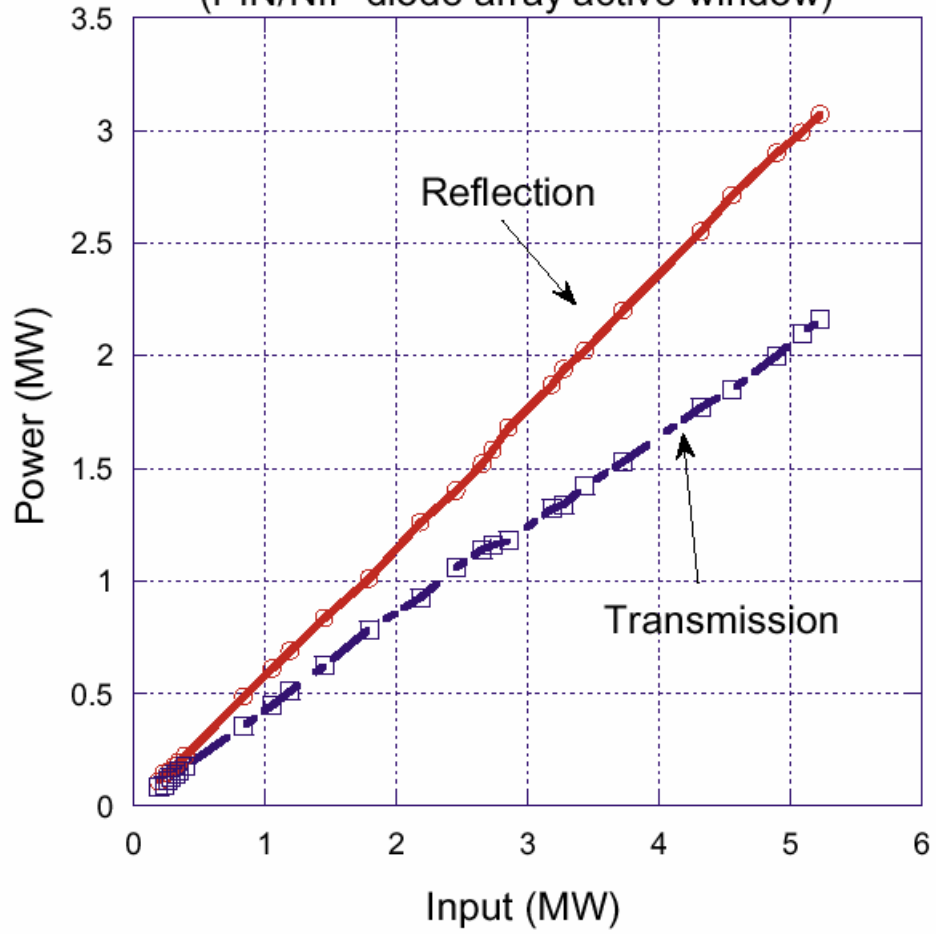
- Setup

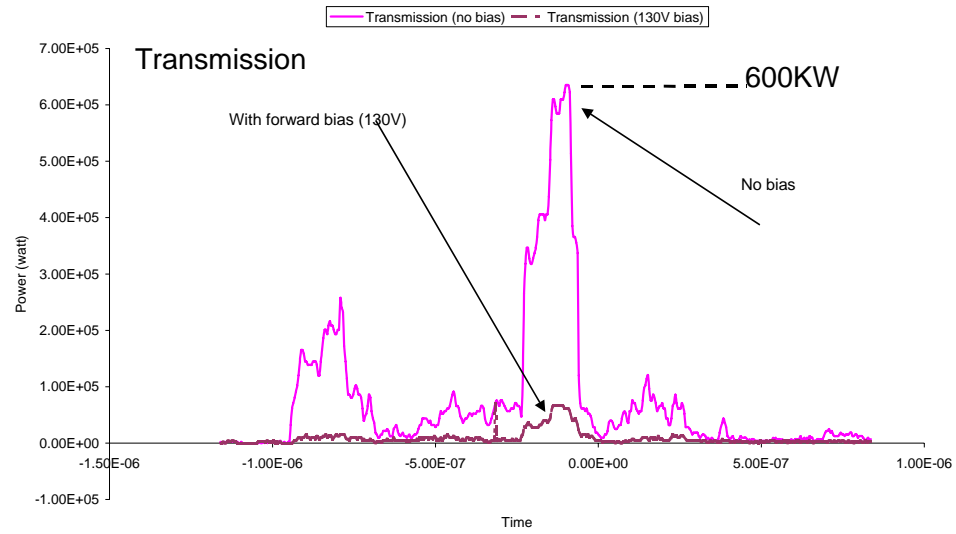
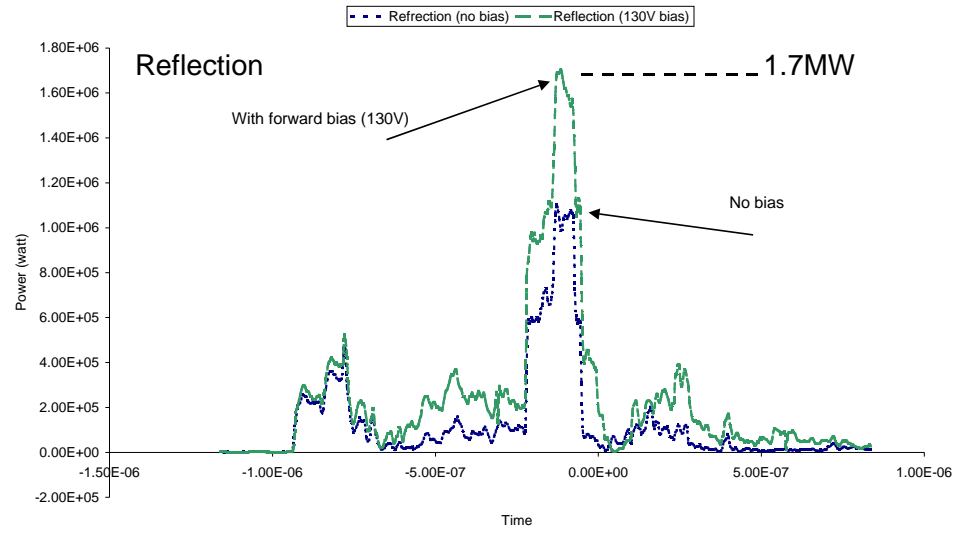


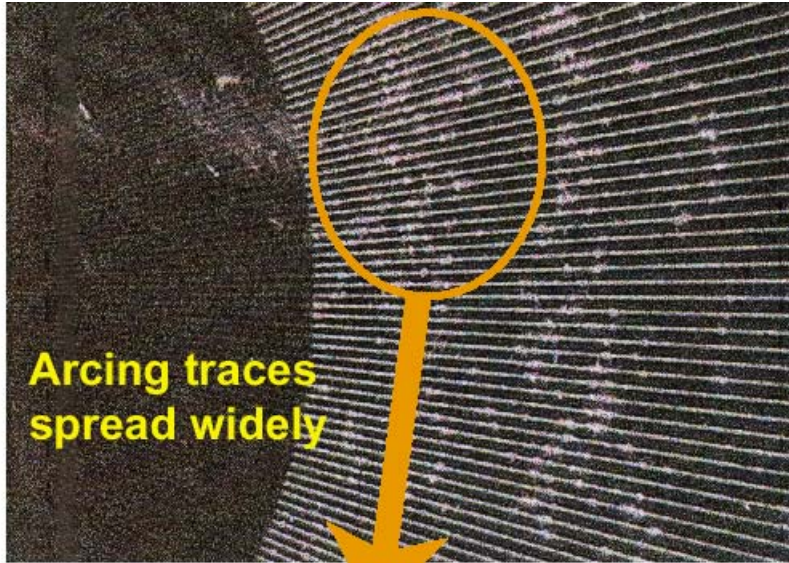
- SLED II output pulse width ~ 150nsec, up to ~10MW can be produced by this system
- Purpose:
 - Investigating failure modes with increasing electric field strength of RF signals
 - Demonstration of switching capabilities at a multi-megawatt power levels at X-band



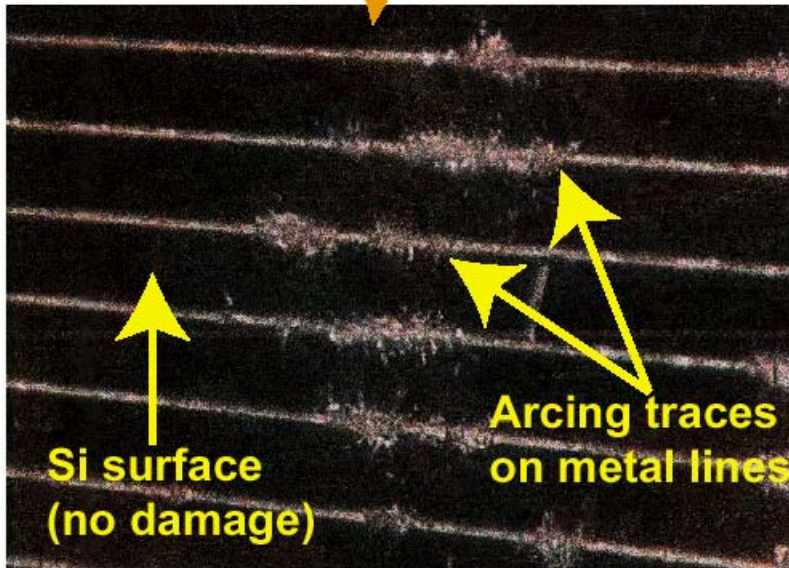
Input vs reflection & transmission
(PIN/NIP diode array active window)





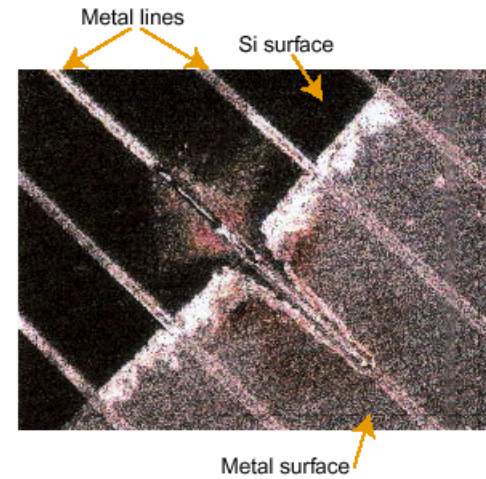


**Arcing traces
spread widely**



**Si surface
(no damage)**

**Arcing traces
on metal lines**



Metal lines

Si surface

Metal surface